

# GSM2310KZ

## 20V N-Channel MOSFETs

### Product Description

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for high efficiency fast switching applications.

### Features

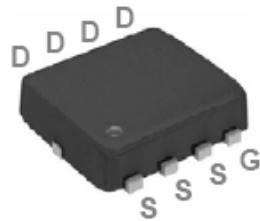
- 20V, 30A,  $R_{DS(ON)}=10m\Omega@V_{GS}=10V$
- Improved dv/dt capability
- ESD Protection Diode Embedded
- Green Device Available
- DFN3X3-8L package design

### Applications

- MB / VGA / Vcore
- POL Applications
- SMPS 2<sup>nd</sup> SR
- Li-Battery Protection

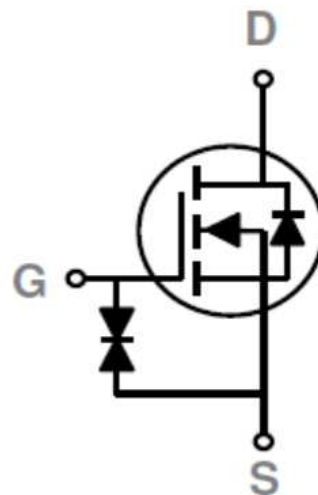
### Packages & Pin Assignments

#### GSM2310KZFF (DFN3X3-8L)

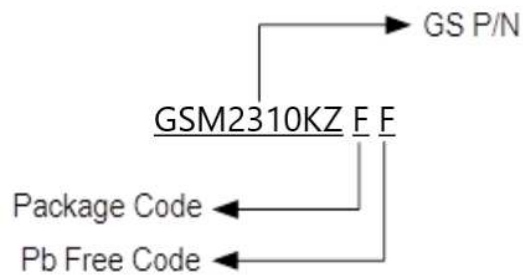


Top View

Pin	Description
1	Source
2	Source
3	Source
4	Gate
5	Drain
6	Drain
7	Drain
8	Drain

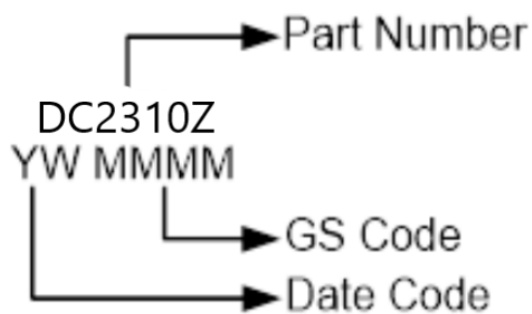


## Ordering Information



Part Number	Package	Quantity
GSM2310KZFF	DFN3X3-8L	5000 PCS

## Marking Information



## Absolute Maximum Ratings

$T_C=25^\circ\text{C}$  Unless otherwise noted

Symbol	Parameter	Typical	Unit
$V_{DS}$	Drain-Source Voltage	20	V
$V_{GS}$	Gate-Source Voltage	$\pm 10$	V
$I_D$	Continuous Drain Current (Chip Limitation)	$T_C=25^\circ\text{C}$	30
		$T_C=100^\circ\text{C}$	19
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	120	A
$P_D$	Power Dissipation ( $T_C=25^\circ\text{C}$ )	26	W
	Power Dissipation (Derate above $25^\circ\text{C}$ )	0.21	W/ $^\circ\text{C}$
$T_J$	Operating Junction Temperature Range	-55 to +150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient	62	$^\circ\text{C}/\text{W}$
$R_{\theta JC}$	Thermal Resistance-Junction to Case	4.8	$^\circ\text{C}/\text{W}$

## Electrical Characteristics

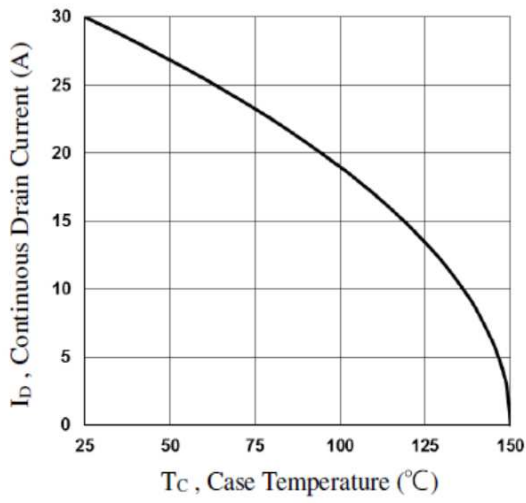
T<sub>J</sub>=25°C Unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	20			V
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	0.3	0.6	1	V
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±10V			±100	nA
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V			1	μA
		V <sub>DS</sub> =16V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C			10	
I <sub>S</sub>	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current			30	A
I <sub>SM</sub>	Pulsed Source Current				60	
R <sub>DS(on)</sub>	Drain-Source On-Resistance	V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A		8	10	mΩ
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =3A		9.5	12	
		V <sub>GS</sub> =1.8V, I <sub>D</sub> =2A		12	17	
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> =5A		12		S
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =1A			1	V
<b>Dynamic</b>						
Q <sub>g</sub>	Total Gate Charge <sup>2,3</sup>	V <sub>DS</sub> =10V, V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A		16.9	26	nC
Q <sub>gs</sub>	Gate-Source Charge <sup>2,3</sup>			1.1	3	
Q <sub>gd</sub>	Gate-Drain Charge <sup>2,3</sup>			4	7	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =10V, V <sub>GS</sub> =0V, f=1MHz		1020	1480	pF
C <sub>oss</sub>	Output Capacitance			160	240	
C <sub>rss</sub>	Reverse Transfer Capacitance			110	160	
t <sub>d(on)</sub>	Turn-On Time <sup>2,3</sup>	V <sub>DD</sub> =10V, I <sub>D</sub> =1A, V <sub>GS</sub> =4.5V, R <sub>G</sub> =25Ω		6.8	13	ns
t <sub>r</sub>				20	38	
t <sub>d(off)</sub>	Turn-Off Time <sup>2,3</sup>			41.8	79	
t <sub>f</sub>				13.2	25	
R <sub>g</sub>	Gate Resistance		V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		2	

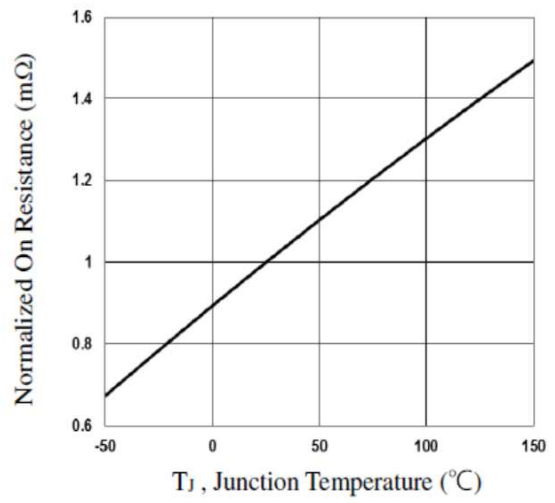
Note :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2. The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%.
3. Essentially independent of operating temperature.

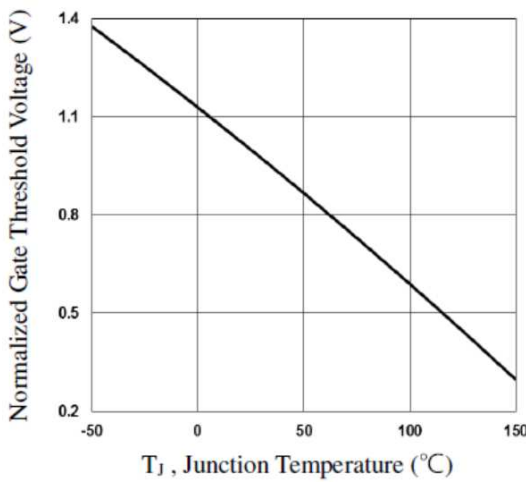
## Typical Performance Characteristics



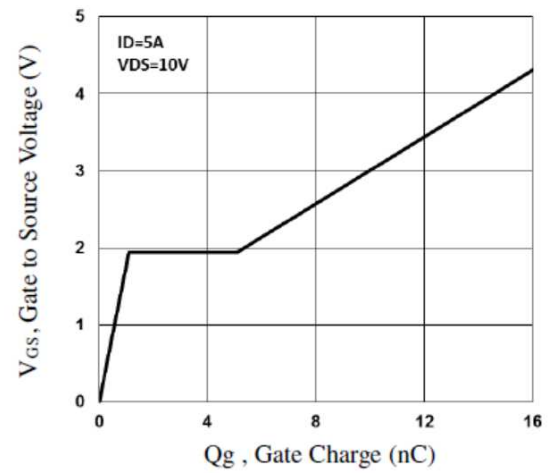
**Fig.1 Continuous Drain Current vs. Tc**



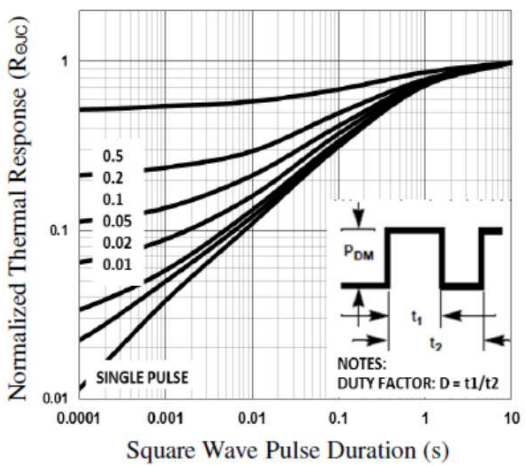
**Fig.2 Normalized RDS(on) vs. Tj**



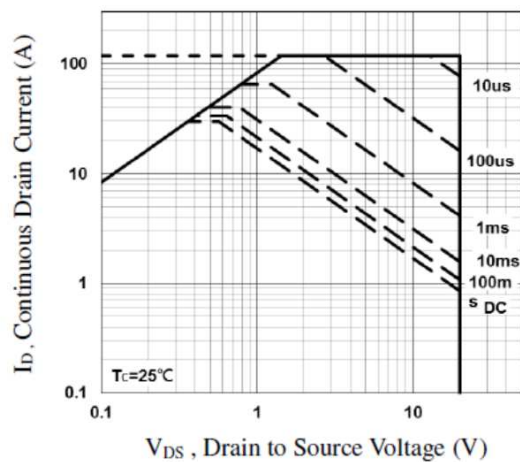
**Fig.3 Normalized Vth vs. Tj**



**Fig.4 Gate Charge Waveform**



**Fig.5 Normalized Transient Response**



**Fig.6 Maximum Safe Operation Area**

Typical Performance Characteristics (Continue)

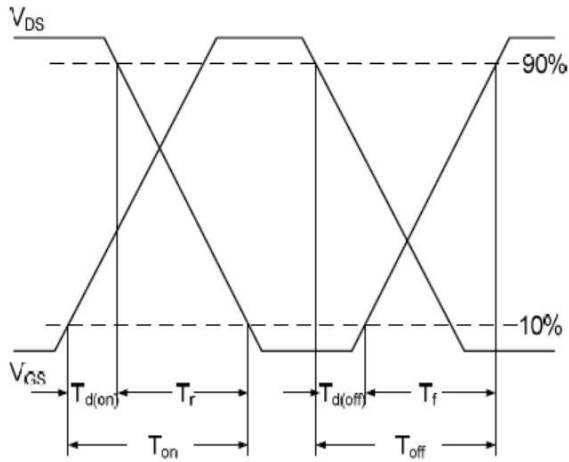


Fig.7 Switching Time Waveform

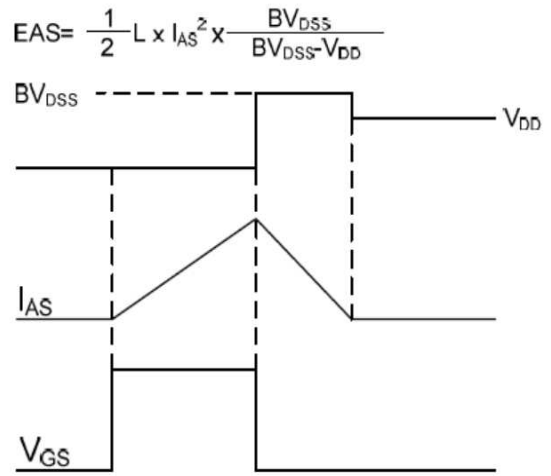
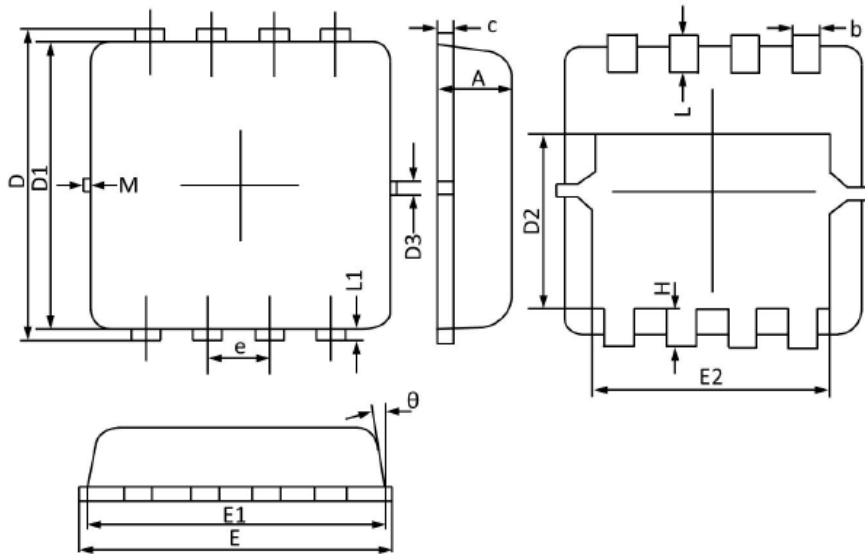


Fig.8 EAS Waveform

## Package Dimension

### DFN3X3-8L







### Dimensions



Symbol	Millimeters		Inches	
	Min	Max	Min	Max
<b>A</b>	0.700	0.800	0.028	0.031
<b>b</b>	0.250	0.350	0.010	0.013
<b>c</b>	0.100	0.250	0.004	0.009
<b>D</b>	3.250	3.450	0.128	0.135
<b>D1</b>	3.000	3.200	0.119	0.125
<b>D2</b>	1.780	1.980	0.070	0.077
<b>D3</b>	0.130 (REF)		0.005 (REF)	
<b>E</b>	3.200	3.400	0.126	0.133
<b>E1</b>	3.000	3.200	0.119	0.125
<b>E2</b>	2.390	2.590	0.094	0.102
<b>e</b>	0.650 (BSC)		0.026 (BSC)	
<b>H</b>	0.300	0.500	0.011	0.019
<b>L</b>	0.300	0.500	0.011	0.019
<b>L1</b>	0.130 (REF)		0.005 (REF)	
<b>θ</b>	0°	12°	0°	12°
<b>M</b>	0.150 (REF)		0.006 (REF)	

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